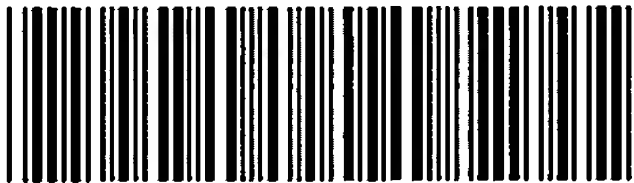


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/624,671	NAKAMURA ET AL.	
	Examiner	Art Unit	
	Helen O. Chu	1745	

SEARCHED			
Class	Subclass	Date	Examiner
429	309	6/9/2006	HC
429	307	6/9/2006	HC
429	303	6/9/2006	HC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Edan and Palm (Inventor Search)	6/9/2006	HC
East Search	6/9/2006	HC